TC044125 Series







◆特征:

- 铁硅铝磁芯,环氧涂层
- 铁芯损耗低于铁粉芯
- 低直流电阻和高饱和电流
- 磁芯由 UL 热缩管包覆以提供 优良的机械和环境保护
- 良好的温度稳定性和频率特性
- 适用于波峰焊接
- 符合 RoHS,无卤和 REACH

◆用途:

- 电源, 开关电路
- 大电流、低压转换器
- 输出扼流圈
- 功率因数校正(PFC)

◆环境:

工作温度: -40℃ 至+125℃
 (包括线圈自身温升)

◆试验设备:

- 电感值:HP4284A, HP4285A 或同等仪器
- 电流:HP4284+42841A 或同等仪器
- 直流电阻: Chroma 16502 或同等仪器

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◆产品型号:

Features:

- Sendust Core with epoxy coating
- Lower Core Losses than Iron Powder Cores
- Low DC resistance and High saturation current
- Core is encapsulated by UL heat shrink tube to provide excellent mechanic and environmental protection
- Good Temperature Stability and Frequency Characteristics
- Suitable for wave soldering
- RoHS, Halogen Free and REACH Compliance

Applications:

- Power supplies, Switching Circuits
- High current, low voltage converters
- Output chokes
- Power factor correction (PFC)

Environmental Data:

Operating Temperature: -40°C to +125°C
 (Including coils self-temperature rise)

Test Equipment:

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- L:HP4284A or HP4285A LCR meter or equivalent
- Isat & Irms: HP4284+42841A or equivalent
- DCR:Chroma 16502 or equivalent

Product Identification:

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	1	
		类型 Type
	TC	环形电感 Toroid Inductors
•	4	X

公称电感量				
Nominal inductance				
100	10uH			

2	1317				
外形尺寸	外形尺寸(OD×Ht) (mm)				
External Dir	mensions (OD×Ht)				
	(mm)				
044125 14.5×7.5					
5					

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公差 Inductance Tolerance	
J:±5%,K: ±10%, L: ±15%	C
M: ±20%,P: ±25%, N: ±30%	1

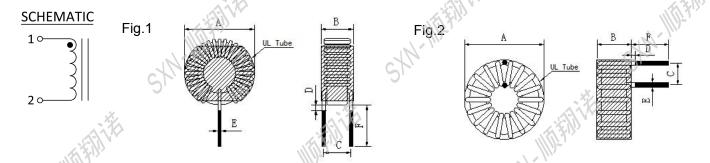


结构代码 Structure Code				
UI	套 管 Black	UL		
UL	Tube 125℃			



◆外观尺寸:

Shape and Dimensions (dimensions are in mm):



* Provide customized services for customers

Part No	ITEM							
T all INO	Shape	Α	В	С	D	Е	F	Structure
TC044125-100M-UL	Fig.1	14.5 Max	7.5Max	6.0 Ref	1.0 Max	0.8±0.1	6.0 Min	大式
TC044125-220M-UL	Fig.1	14.5 Max	7.5Max	6.0 Ref	1.0 Max	0.8±0.1	6.0 Min	立式
TC044125-330M-UL	Fig.1	14.5 Max	7.5Max	5.5 Ref	1.0 Max	0.7±0.1	6.0 Min	立式
TC044125-470M-UL	Fig.1	14.5 Max	7.5Max	5.5 Ref	1.0 Max	0.6±0.1	6.0 Min	立式
TC044125H-100M-UL	Fig.2	14.5 Max	7.5Max	5.5 Ref	1.0 Max	0.8±0.1	6.0 Min	
TC044125H-220M-UL	Fig.2	14.5 Max <	7.5Max	5.5 Ref	1.0 Max	0.8±0.1	6.0 Min	
TC044125H-330M-UL	Fig.2	14.5 Max	7.5Max	4.5 Ref	1.0 Max	0.7±0.1	6.0 Min	臣式
TC044125H-470M-UL	Fig.2	14.5 Max	7.5Max	4.5 Ref	1.0 Max	0.6±0.1	6.0 Min	九

◆规格特性:

Specifications:

• TC044125 Series Electrical Characteristics (Electrical specifications at 25℃)

Sta	Inductance DCR Rated Current $L(\mu H)$ Tole $(m \Omega)$ (A)		DCR Rated Current		Hi-pot tes	
Part No			Coil-Core			
	'@1KHz	16-5	Max	Max	GOII-GOIC	
TC044125-100M-UL	10	±20%	11.5	4.5	AC500V,3mA,60s	
TC044125H-100M-UL	10	12070	11.5	4.5	A0300 V,3111A,003	
TC044125-220M-UL	22	±20%	17.5	3.0	AC500V,3mA,60s	
TC044125H-220M-UL	ZZ	±20%	17.5	3.0	AC300V,SIIIA,00S	
TC044125-330M-UL	33	±20%	24.5	2.5	AC500V,3mA,60s	
TC044125H-330M-UL	715 33	±2U%	24.5	2.5	AC300V,SIIIA,00S	
TC044125-470M-UL	47	. 200/	27/2	2.0	A 0.500 V 2 A 00 -	
TC044125H-470M-UL	47	±20%	35.0	2.0	AC500V,3mA,60s	

- Rated Current: the actual value of DC current when the temperature rise is∆T 40°C (Ta=25°C)
- Special remind:Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application



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◆产品包装:

• In bag pakeage

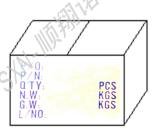




PE 袋

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Outside Carton 不足整箱用内盒或填充物装满

SXN-IIII 等消光

Part No.	PE 胶袋每袋数量	外箱		
TC044125	300PCS	3000PCS		

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◆可靠性测试:

Reliability Testing:

▼り非性测试:		Reliability Testing:		
Items	Requirements	Test Methods and Remarks		
Terminal Strength Reference docu ments: GB/T 2423.60-2008 端子強度(SMT)	1. Pulling test: Define: A: sectional area of terminal A ≤ 8mm2 force ≥ 5N time:30sec 8mm2 <a 10n="" 10sec="" 2.solder="" 20mm2="" 20mm2<a="" 20n="" 3.meet="" above="" any="" force="" loose="" paste="" requirements="" td="" terminal<="" the="" thickness:0.12mm="" time:="" without="" ≤="" ≥=""><td>Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.</td>	Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.		
erminal Strength Reference docu ments: GB/T 2423.60-2008 端子強度(DIP)	1.Terminal diameter(d) mm 0.35 <d 0.50applied="" 0.80applied="" 1.25applied="" 10sec2.terminal="" 10sec3.terminal="" 10sec4.terminal="" diameter(d)="" duration:="" force:10n="" force:20n="" force:5n="" mm0.50<d="" mm0.80<d="" mmd=""> 1.25Applied force:40N Duration: 10sec5.Meet the above requirements without any loose terminal.</d>	Pull Force:the force shall be applied gradually to the terminal and thenmaintained for 10 seconds.		
Resistance to Flexure JIS C 5321:1997 抗弯曲性试验	1.No visible mechanical damage.	1.Solder the inductor to the test jig (glass epoxy board 2.shown in Using a leadfree solder. Then apply a force in the direction shown 3.Flexure: 2mm. 4.Pressurizing Speed: 0.5mm/sec. 5.Keep time: 30 sec.		
Dropping Reference documents: GB/T 2423.7-2018 落下試驗	1.No case deformation or change inappearance. 2.No short and no open.	1.Drop the packaged products from 1m high in 1 angle, 3 ridges and 6surfaces, twice in each direction.		
Solderability Reference documents: GB/T 2423.28-2005 可焊性试验	1.No visible mechanical damage. 2.Wetting shall exceed 75% coverage for 3.Terminals must have 95% minimum solder coverage	 1.Solder temperture:240 ± 2°C 2.Duration: 3 sec. 3. Solder: Sn/3.0Ag/0.5Cu. 4.Flux: 25% Resin and 75% ethanol in weight 		



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Items	Requirements	Test Methods and Remarks
Vibration Reference documents: GB/T 2423.10-2019 振動試验	1.No visible mechanical damage. 2. Inductance change: Within ±10%. 3.Q factor change: Within ±20%. Cu pad Solder mask Glass Epoxy Board	1.Solder the inductor to the testing jig (glass epoxy boardshown in) using leadfree solder. 2.The inductor shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the frequency being varieduniformly between the approximate limits of 10 and 55 Hz. 3.The frequency range from 10 to 55 Hz and return to 10 Hz shallbe traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions(total of 6 hours).
SXN-IIII	Within ≤ 30%)	1.Start at (85~125°C) for T time, rush to (-55~40°C) for T time as one cycle, go through100 cycles.
Thermal Shock Reference documents: GB/T 2423.22-2012	3.Q factor change: Within ±20%.	2.Transforming interval: Max. 20 sec.3.Tested cycle: 100 cycles.4.The chip shall be stabilized at normal condition for 1~2 hours
Method Na 冷热冲击试验	CXN-IIII jiji iji	125°C/85°C 30 min. 30 min. Ambient 30 min. Temperature 30 min. 20sec. (max.)
51.	1.No visible mechanical damage.2. Inductance change: Within ±10%.(Mn-Zn: Within ≤30%)	1.Temperature:M(-55~-40±2°ℂ) 2.Duration: 96±2 hours 3.The chip shall be stabilized at normal condition for
Low temperature Storage Reference documents: GB/T 2423.1-2008	3.Q factor change: Within ±20%.	1~2 hoursbefore measuring. Room Temp
Method Ab 低温储存试验	CM-III Filit	M°C Temp Low temperature

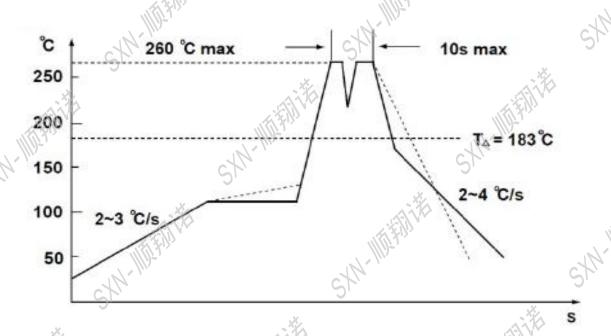


Items	Requirements	Test Methods and Remarks
	1.No visible mechanical damage.	1.Temperature:N(125~85±2℃).
High temperature	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours
Storage	Within ≦30%)	3. The chip shall be stabilized at normal condition
Reference documents:	3.Q factor change: Within ±20%.	for 1~2 hoursbefore measuring.
GB/T 2423.2-2008	<i>x</i> .	Temp High temperature
Method Bb	A STATE OF THE STA	N'C
高温储存试验		Room
问価间行队巡	1 - 11/1/2.	Temp Test
19/11/11	2/2	0 96H 97H 98H Time
Sr'	1.No visible mechanical damage.	1.Temperature: 60±2°C
	2. Inductance change: Within ±10%.(Mn-Zn:	2.Humidity: 90% to 95% RH.
Damp Heat	Within ≦30%)	3 Duration: 96±2 hours.
(Steady States)	3.Q factor change: Within ±20%.	4. The chip shall be stabilized at normal condition
Reference documents:	M. W.	for 1~2 hoursbefore measuring.
GB/T 2423.3-2016	2,	Temp & Humidity
恒定湿热试验	.*.	93%RH High temperature High humidity
		Room Conditions
		0 Test 0 96H 97H 98H Time
Lloot buddings of	1.No significant defects in appearance.	
Heat endurance of Reflow soldering	2. △ L/L ≦ 10% (Mn-Zn: △ L/L ≦ 30%)	1.Refer to the above reflow curve and go through the reflow for twice.
Reference documents:	3. ∆ Q/Q ≤ 30% (SMD series only)	2.The peak temperature : 260+0/-5℃
GJB 360B-2009	4. △ DCR/DCR ≦ 10%	2. This peak temperature : 200 to 70 0
回流焊耐热性试验		(1) 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
□ P.P. 1.141 W. 1∓ % (4∞	No case deformation or change in	To dip parts into IPA solvent for 5±0.5Min,then
Resistance to solvent	appearance or obliteration of marking	drying them at room temp for 5Min,at last ,to
test	3	brushing making 10 times.
Reference documents:		
IEC 68-2-45:1993		
耐溶剂性试验	11/1/2	M-IIIs
M-IIIs	eth,	SKI
Overload test	1.During the test no smoke, no peculiar,	×.
Reference documents:	smell, no fire	A THE STATE OF THE
JIS C5311-6.13	2.The characteristic is normal after test	Apply twice as rated current for 5 minutes.
过负荷试验		1 . Ms
la.	My This	c X
voltage resistance test	1.During the test no breakdown	
Reference documents:	2.The characteristic is normal after test	For parts with two coils
MIL-STD-202G Method		2. DC1000V, Current: 1mA, Time: 1Min.
301		Refer to catalogue of specific products
绝缘耐压测试	(a) -	S. F. G. C. To Galangue of Specific products
171	C X/M	Sr'



◆推荐无铅波峰焊接曲线:

Lead-free the recommended Wave soldering (DIP-TYP)



The recommended reflow conditions as above graph, is set according to our soldering equipment. DUE to various manufactures may have different reflow soldering equipment, products, process conditions, set methods. And so on, when setting the reflow conditions, Please adjust and confirm according to users' environment/equipment.

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使用注意事项

REMINDERS FOR USING THESE PRODUCTS



● 保存时间为12 个月以内,保存条件(温度5~40°C以下、湿度35 ~ 66%RH 以下),需充分注意。 若超过保存时间,端子电极的可焊性将可能老化。

The storage period is within 12 months. Be sure to follow the storage conditions (temperature: 5~40°C, humidity: 35 to 65% RH or less). If the storage period elapses, the soldering of the terminal electrodes may deteriorate.

• 请勿在气体腐蚀环境(盐、酸、碱等)下使用和保存。

Do not use or store in locations where there are conditions such as gas corrosion (salt, acid, alkali, etc.).

- 手上的油脂会导致可焊性降低,应避免用手直接接触端子。
 - Don't touch electrodes directly with bare hands as oil secretions may inhibit soldering Always ensure optimum conditions for soldering.
- 请小心轻拿轻放,避免由于产品的跌落或取出不当而导致的损坏。
 - Please always handle products carefully to prevent any damage caused bydropping down or inappropriate removing.
- 端子过度弯曲会导致断线,请不要过度弯曲端子。
 - Don't bend the terminals with excessive stress in case of any wire fracture.
- 不要清洗产品, 如需要清洗时请联系我司。
 - Don't rinse coils by yourself and please contact SXN if necessary.
- 请勿将本产品靠近磁铁或带有磁力的物体
 - Don't expose the products to magnets or magnetic fields
- 在实施焊接前,请务必进行预热。预热温度与焊接温度及芯片温度的温度差要在150°C 以内。
 Before soldering, be sure to preheat components. The preheating temperature should be set so that the temperature difference between the solder temperature and chip temperature does not exceed 150°C.
- 安装后的焊接修正应在规格书规定的条件范围内。若加热过度可能导致短路、性能降低、寿命减少。
 Soldering corrections after mounting should be within the range of the conditions determined in the specifications. If overheated, a short circuit, performance deterioration, or lifespan shortening may occur.
- 装置会因通电而自我发热(温度上升),因此在热设计方面需留有充分余地。
 Self heating (temperature increase) occurs when the power is turned ON, so the tolerance should be sufficient for the set thermal design.
- 非磁屏蔽型在基板设计时需注意配置线圈,受到电磁干扰可能会导致误动作。
 Carefully lay out the coil for the circuit board design of the non-magnetic shield type. A malfunction may occur due to magnetic interference.
- 当本公司产品使用在一般电子设备以外的场合,如:车载,医疗设备,军用,航空航天等,请务必联繫本公司营业部门, 如超出本公司产品使用条件而引起的机器故障时,本公司概不负责。
 - If SXN product will be applied in area like automotive product, medical equipment, military and aerospace except generalelectronic device, please keep SXN sales informed in advance. SXN shall not be held liable for any malfunction or breakdowncaused by using product in the condition which is inconsistent with that recommended by SXN.